Machine Learning for Radar and Communication Signal Processing

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Message from the Guest Editors

This Special Issue is aimed at addressing issues in state-of-the-art machine learning approaches applicable in radar, communications and electronic countermeasures domains, providing cross-disciplinary ideas to address present and future challenges. Topics of interest include, but are not limited to:

- Blind channel and signal characterization;
- Source separation;
- Signal recognition;
- Automatic modulation classification;
- Spectrum sensing;
- Positioning and navigation;
- Cognitive radio communications;
- Radar image processing;
- Autonomous navigation.

Welcome to contribution.

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Special Issue

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Message from the Editor-in-Chief

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